Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/808,829	WEHNER, KATHRYN M.
Examiner	Art Unit

Y Quach Lee

2875

	SEAR	EARCHED		
Class	Subclass	Date	Examiner	
362	240 241 294 348 511 517 518	6/7/2005	YMY	
	545 547			
	551 555 800			

TNI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

(INCLUDING SE	ARCH STRATEGY	<u>') </u>
	DATE	EXMR
NONE	6/7/2005	YMY
	3253	